TOSHIBA Photocoupler

IRED & Photo IC

TLP559(IGM)

Transistor Inverters
Air Conditioner Inverters
Line Receivers
Intelligent Power Modules (IPMs) Interfaces

The TOSHIBA TLP559(IGM) consists of a high-output infrared emitting diode optically coupled to a high-speed photodiode with a transistor amplifier.

The TLP559(IGM) has no internal base connection. The Faraday shield in the photodetector chip provides an effective common-mode noise transient immunity.

The TLP559(IGM) guarantees minimum and maximum propagation delay time, a relative time difference between the rise and fall time, and common-mode transient immunity. Therefore, the TLP559(IGM) is suitable for an isolation interface between an Intelligent Power Module (IPM) and a control IC in motor control applications.

- Isolation Voltage: 2500 Vrms (min)
- Common-Mode Transient Immunity: ±10 kV/μs (min) @VCM = 1500 Vp-p
- Switching Time: tpHL, tpLH = 0.1μs (min), = 0.8μs (max)

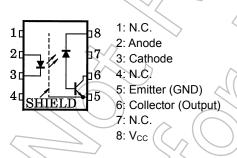
@IF = 10 mA, VCC = 15 V, RL = 20 k
$$\Omega$$
, Ta = 25°C

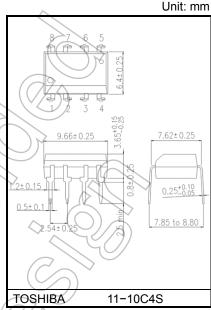
Switching Time Dispersion: 0.7 μs (max)

- TTL Compatible
- UL-recognized: UL 1577, File No.E67349
- cUL-recognized: CSA Component Acceptance Service No.5A

File No.E67349

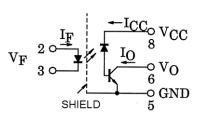
Pin Configuration (Top view)





Weight: 0.54 g (typ.)

Schematic



Start of commercial production 1995-01



Absolute Maximum Ratings (Ta = 25°C)

	CHARACTERISTIC		SYMBOL	RATING	UNIT
	Forward Current	(Note 1)	lF	25	mA
	Pulse Forward Current	(Note 2)	IFP	50	mA
ΓE	Peak Transient Forward Current	(Note 3)	IFPT	1	Α
	Reverse Voltage		VR	5	٧
	Diode Power Dissipation	(Note 4)	PD	45	mW
	Output Current		lo (7/8	mA
'OR	Peak Output Current		IOP	16	mA
DETECTOR	Output Voltage		Yo	-0.5 to 20	٧
DET	Supply Voltage		Voc	-0.5 to 30	٧
	Output Power Dissipation	(Note 5)	Po	100	mW
Оре	rating Temperature Range		Topr	-55 to 100	(°C)
Storage Temperature Range		(7)	Tstg	-55 to 125	%
Lea	d Solder Temperature(10 s)	(Note 6)) T _{sol}	260	Ç
Isola	ation Voltage(AC, 60 s, R.H.≤60 %)	(Note 7)	BVs	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.8 mA above 70 °C.

(Note 2) 50 % duty cycle, 1 ms pulse width. Derate 1.6 mA/°C above 70 °C.

(Note 3) Pulse width PW $\leq 1 \mu s,\,300$ pps.

(Note 4) Derate 0.9 mW/°C above 70°C.

(Note 5) Derate 2 mW/°C above 70°C.

(Note 6) Soldering portion of lead : up to 2mm from the body of the device.

(Note 7) Device considers a two-terminal device : pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.



Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
ED	Forward Voltage	V _F	I _F = 16 mA	_	1.65	1.85	V
	Forward Voltage Temperature Coefficient	ΔVϝ /ΔΤα	IF = 16 mA	_	-2	_	mV /°C
=	Reverse Current	IR	V _R = 5 V		_	10	μΑ
	Capacitance between Terminal	СТ	V = 0 V, f = 1 MHz		45	_	pF
DETECTOR	High Level Output Current	IOH (1)	I _F = 0 mA, V _{CC} = V _O = 5.5 V		3	500	nA
		IOH (2)	I _F = 0 mA, V _{CC} = 30 V V _O = 20 V	/	_	5	
		Іон	IF = 0 mA, V _{CC} = 30 V V _O = 20 V, Ta = 70 °C	_	_	50	μΑ
	High Level Supply Voltage	Іссн	IF = 0 mA, V _{CC} = 30 V	_	0.01	1	μΑ
	Supply Voltage	Vcc	ICC = 0.01 mA	30	JE!	_	V
	Output Voltage	Vo	I _O = 0.5 mA	20 🕜	1	_	V

Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL TEST CONDITION	MIN	TYP.	MAX	UNIT
Current Transfer Ratio	I _F = 10 mA, V _{CC} = 4.5 V V _Q = 0.4 V	25	35	75	%
Current Transfer Ratio	I_O / I_F $I_F = 10 \text{ mA}, V_{CC} = 4.5 \text{ V}$ $V_O = 0.4 \text{ V}, T_A = -25 \text{ to } 100 \text{ °C}$	15	_	ı	70
Low Level Output Voltage	V _{OL} I _F = 16 mA, V _{CC} = 4.5 V I _O = 2.4 mA	_	_	0.4	V

Isolation Characteristics (Ta = 25°C)

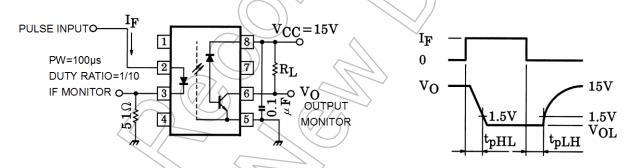
CHARACTERISTIC	SYMBOL	TEST CONDITIO	N	MIN	TYP.	MAX	UNIT
Capacitance Input to Output	Cs	V = 0 V, f = 1 MHz	(Note 7)	_	0.8	-	pF
Isolation Resistance	Rs	R.H. ≤ 60 %, V _S = 500 V	(Note 7)	5×10 ¹⁰	10 ¹⁴	_	Ω
Isolation Voltage	BVs	AC, 60 s	(Note 7)	2500	_	_	Vrms

Switching Characteristics (Ta = 25°C, Vcc = 15 V)

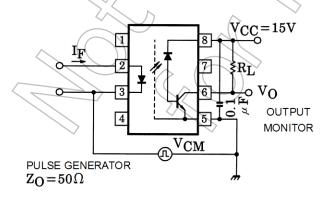
CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
	t _P HL t _P LH		I_F = 10 mA, R_L = 20 kΩ	0.1	0.45	0.8	μs
			I_F = 10 mA, R_L = 20 kΩ Ta = 0 to 85 °C	0.1	0.45	0.9	
Propagation Delay Time (L→H)		1	I _F = 10 mA, R _L = 20 kΩ Ta = -25 to 100 °C	0.1	0.45	1.0	
			I_F = 10 mA, R_L = 20 kΩ		0.25	0.7	μs
Switching Time Dispersion between ON and OFF	t _{pLH} -t _{pHL}		I_F = 10 mA, R_L = 20 kΩ Ta = 0 to 85 °C	}	0.25	0.8	
Disposor Sections of the disposor			I _F = 20 mA, R _L = 20 kΩ Ta = -25 to 100 °C	_	0.25	0.9	
Common Mode Transient Immunity at Logic High Output (Note 8)	СМн	2	$I_F = 0 \text{ mA},$ $V_{CM} = 1500 \text{ V}_{p-p},$ $R_L = 20 \text{ k}\Omega$	10000	15000		V /μs
Common Mode Transient Immunity at Logic Low Output (Note 8)	CML	2	$I_F = 10 \text{ mA},$ $V_{CM} = 1500 \text{ Vp-p},$ $R_L = 20 \text{ k}\Omega$	-10000	-15000	· _	V /μs

(Note 8) CM_L is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state(Vo<1 V).</p>
CM_H is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state(Vo>4 V).

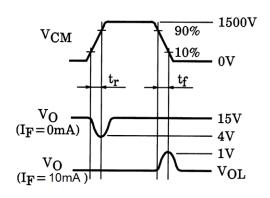
Test Circuit 1: Switching time test circuit



Test Circuit 2: Common mode noise immunity test circuit



$${\rm CM}_{H} = \frac{1200(V)}{{\rm t}_{\rm r}(\mu {\rm s})} \,, \ \, {\rm CM}_{L} = \frac{1200(V)}{{\rm t}_{\rm f}(\mu {\rm s})} \,$$



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